

<b>Notice of References Cited</b>	Application/Control No. 10/801,575		Applicant(s)/Patent Under Reexamination WATANABE ET AL.	
	Examiner Khawar Iqbal		Art Unit 2686	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0064758 A1	04-2003	Mizuta et al.	455/566
*	B	US-2003/0153372 A1	08-2003	Shimamura et al.	455/575
*	C	US-2004/0248628 A1	12-2004	Taninai, Minoru	455/575.3
*	D	US-6,958,902 B2	10-2005	Tseng et al.	361/681
*	E	US-6,804,861 B2	10-2004	Hsu, Hsiang-Ti	16/366
*	F	US-6,830,456 B2	12-2004	Obermeyer, John R.	439/6
*	G	US-6,867,961 B2	03-2005	Choi, Phil-kyu	361/681
*	H	US-6,876,545 B2	04-2005	Tseng et al.	361/681
*	I	US-2003/0083063 A1	05-2003	Wang et al.	455/427
*	J	US-2002/0155740 A1	10-2002	Sawada et al.	439/165
*	K	US-2003/0203747 A1	10-2003	Nagamine, Yasuo	455/575.3
*	L	US-2004/0110529 A1	06-2004	Watanabe et al.	455/550.1
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	W	
	X	

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